

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	10/701841	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 07:58
L2	14	US-5164805-\$.DID. OR US-5282921-\$.DID. OR US-5519336-\$.DID. OR US-5576630-\$.DID. OR US-5585736-\$.DID. OR US-5674760-\$.DID. OR US-0601261-\$.DID. OR US-6046599-\$.DID. OR US-6160415-\$.DID. OR US-6175245-\$.DID. OR US-6257053-\$.DID. OR US-6275059-\$.DID. OR US-6326220-\$.DID. OR US-0410353-\$.DID.	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:04
L3	1	2002/0140039 2002/0167008 2002/0180474 2003/0071317	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:06
L4	1	2002/0140039 2002/0167008 2002/0180474	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:04
L5	0	2002/0140039	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:06
L6	0	2002/0167008	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:06
L7	1	"20020167008"	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:06
L8	41711	test\$3 near4 ('soi' silicon-on-insulator wafer substrate)	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 09:56

L9	12310	8 and voltage	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:09
L11	3125	9 and ((insulat\$3 buried) near3 (layer region))	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:13
L12	1309	11 and probe	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:14
L13	391	12 and (voltage near5 (substrate wafer))	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:17
L15	172	13 and (measur\$4 with (votage current bias))	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:20
L16	4	15 and (sweep\$4 with (votage current bias))	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 08:19
L17	73	test\$3 near4 ('soi' silicon-on-insulator)	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 09:57
L18	54	17 and voltage	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 09:57
L19	14	18 and probe	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:01
L20	1741	438/14.ccls.	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:02
L21	695	20 and voltage	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:04

L22	270	21 and probe	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:02
L23	208	22 and measur\$4	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:03
L24	180	23 and current	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:03
L25	12	24 and sweep\$4	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:03
L26	9	12 and 17	US-PGPU B; USPAT; EPO; JPO	OR	ON	2005/03/10 10:04